



Object Detection and Image Classification

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Message from the Guest Editors

Rapid advances in machine learning and artificial intelligence in the last decade have enabled various objects in images to be effectively identified and classified. This advancement makes the detection of objects in various application domains possible, such as detecting cancerous cells in microscopic images, classifying plants and insects in natural environments and distinguishing deepfake images from real ones. However, various challenges still need to be resolved before automatic object objection applications can be widely deployed.

This Special Issue invites high-quality papers that present novel ideas in object detection and classification, the explanation of detection decision and the improvement on acceptability in any application domains. Areas relevant to this Special Issue include, but are not limited to, the following:

- Object detection and tracking;
- Classification of images;
- Deepfake detection;
- Explainable AI on object detection;
- Object localization in images;
- Augmented reality;
- Autonomous vehicles and robots;
- Umpire Decision Review System;
- Remote sensing;
- Disease detection and diagnosis;
- Biometrics.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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